

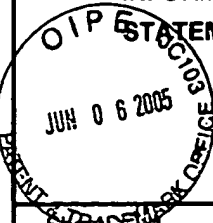
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> JUN 06 2005		Application Number	10/607,840		
		Filing Date	June 27, 2004		
		First Named Inventor	Gregory R. Hanson		
		Group Art Unit	2877		
		Examiner Name			
Sheet	1	of	1	Attorney Docket	UBAT1490-2

### U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code (if known)		
PSL		6078392		06-20-2000	Rasmussen et al.
PSL		6078392		06-20-2000	Thomas et al.

Examiner Initials	Cite No.	FOREIGN PATENT DOCUMENTS			Publication Date MM-DD-YYYY (Number 43)	Name of Patentee or Applicant of Cited Document
		Country Code	Number	Kind Code (if known)		

Examiner Signature	PATRICK CONNALLY	Date Considered	11.29.2005
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### NON-PATENT LITERATURE DOCUMENTS

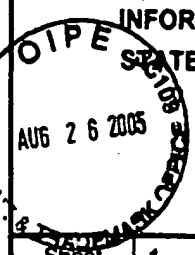
Examiner Initials	Cite No.	Citation
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PJC		Written Opinion of the International Searching Authority from PCT/US2004/012710, January 7, 2005
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